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| Notice of References Cited | Application/Control No. 10/609,016 | | Applicant(s)/Patent Under Reexamination LE ET AL. | |
| | Examiner BINH K. TIEU | | Art Unit 2614 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|-----------------|----------------|
| * | A | US-7,447,173 | 11-2008 | Harris, John M. | 370/328 |
| * | B | US-2001/0036164 | 11-2001 | Kakemizu et al. | 370/331 |
| * | C | US-2003/0147537 | 08-2003 | Jing et al. | 380/277 |
| * | D | US-2004/0024901 | 02-2004 | Agrawal et al. | 709/238 |
| * | E | US-2002/0120844 | 08-2002 | Faccin et al. | 713/168 |
| * | F | US-2003/0224788 | 12-2003 | Leung et al. | 455/435.1 |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
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| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) | | | |
|---|---|---|--|--|--|
| | U | | | | |
| | V | | | | |
| | W | | | | |
| | X | | | | |

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